

**Search Notes**

Application/Control No.

10/748,200

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under  
Reexamination

NAIR ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	51	5/3/2005	PN
//	258	//	/

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
330	51	5/3/2005	PN
//	258	//	//

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR